Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/767,719	OGAWA, HIDEHIKO		
Examiner	Art Unit		
Thomas D. Lee	2624		

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Class	Subclass	Date	Examiner
358	1.15, 402, 440	9/27/2005	TDL
379	100.01	9/27/2005	TDL
379	100.08	9/27/2005	TDL
379	100.13	9/27/2005	TDL
379	100.17	9/27/2005	TDL
updated		2/2/2006	TDL

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